·	Application No.	Applicant(s)	
Notice of Allowability	09/486,561 Examiner	HASHIMOTO, NOBUAKI Art Unit	
·		A Comme	
	David A. Zameke	2891	
The MAILING DATE of this communication appeal all claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	olication. If not include will be mailed in due	ed course. THIS
1. 🛛 This communication is responsive to the amendment filed	<u>5/18/05</u> .		
2. X The allowed claim(s) is/are 8,11,12,14-16,21,22 and 24-26			
3. The drawings filed on 29 May 2001 are accepted by the Ex	aminer.		
 4. Acknowledgment is made of a claim for foreign priority un a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 	been received.		
Copies of the certified copies of the priority documents have			tion from the
International Bureau (PCT Rule 17.2(a)).	differential flavor been received in this i	iational stage applica	non nom me
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be subminished in FORMAL PATENT APPLICATION (PTO-152) which give	ENT of this application. itted. Note the attached EXAMINER's reason(s) why the oath or declarate	S AMENDMENT or N	
CORRECTED DRAWINGS (as "replacement sheets") mus		•	
(a) I including changes required by the Notice of Draftspers	on's Patent Drawing Review (PTO-9	948) attached	
1) hereto or 2) to Paper No./Mail Date			
(b) including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the O	ffice action of	
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the	84(c)) should be written on the drawin ne header according to 37 CFR 1.121(c	gs in the front (not the l).	back) of
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I 	sit of BIOLOGICAL MATERIAL m FOR THE DEPOSIT OF BIOLOGICA	nust be submitted. N NL MATERIAL.	lote the
	•		
Attachment(s)			
1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal Pa	atent Application (PTC)-152)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summary		·
 Information Disclosure Statements (PTO-1449 or PTO/SB/0- Paper No./Mail Date <u>5/26/05</u> 	Paper No./Mail Date 8), 7. ☐ Examiner's Amendm		
4. Examiner's Comment Regarding Requirement for Deposit	8. Examiner's Stateme	nt of Reasons for Allo	wance
of Biological Material	9. Other		
		David A. Zarneke Primary Examiner - August 4, 2005	AU2891

DETAILED ACTION

Examiner's Amendment

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows: Cancel claims 3, 4, 9, 10, 13, and 17-20 as nonelected claims.

Reasons for Allowance

The following is an examiner's statement of reasons for allowance: Prior art could not be located that taught a conductive adhesive said adhesive having a first portion and a second portion, said first portion interposed between a surface of said substrate on which said interconnect pattern is formed and a surface of said semiconductor chip on which said electrodes are formed, said second portion overlapping with said semiconductor chip between said second portion of said adhesive covers all area of lateral surfaces of said semiconductor chip that is substantially perpendicular to the surface of the semiconductor chip on which the electrodes are formed, and a thickness of any part of said second portion of said adhesive is thicker than an interval between the surface of the semiconductor chip on which said electrodes are formed and said interconnect pattern on said substrate.

Art Unit: 2891

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to David A. Zarneke whose telephone number is (571)-272-1937. The examiner can normally be reached on M-Th 7:30 AM-6 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Baumeister can be reached on (571)-272-1722. The fax phone number for the organization where this application is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

Primary Examiner August 4, 2005